



RADIO TEST REPORT

Test Report No. : 30DE0252-HO-01-B-R1

Applicant : DENSO WAVE INCORPORATED
Type of Equipment : Contactless IC Card Reader/Writer
Model No. : PR-450UDM
Test standard : FCC Part 15 Subpart C : 2009
Section 15.207 and 15.225
FCC ID : PZWPR450UDM
Test Result : Complied

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6. This report is a revised version of 30DE0252-HO-01-B. 30DE0252-HO-01-B is replaced with this report.

Date of test: December 16, 2009 to January 20, 2010

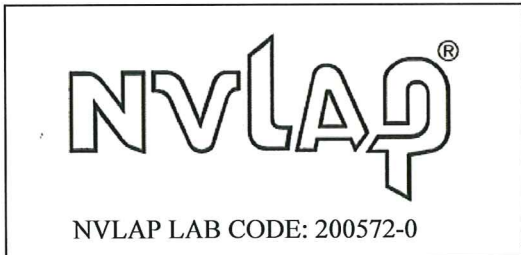
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SECTION 1: Customer information

Company Name : DENSO WAVE INCORPORATED
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SECTION 2: Equipment under test (E.U.T.)

2.1 Identification of E.U.T.

Type of Equipment : Contactless IC Card Reader/Writer
Model No. : PR-450UDM
Serial No. : Refer to Section 4, Clause 4.2
Rating : DC 5V
Receipt Date of Sample : December 11, 2009
Country of Mass-production : Japan
Condition of EUT : Production prototype
(Not for Sale: This sample is equivalent to mass-produced items.)
Modification of EUT : No Modification by the test lab

2.2 Product Description

Model No: PR-450UDM (referred to as the EUT in this report) is the Contactless IC Card Reader/Writer.

Feature of EUT : The PR-450UDM reader/writer, which is easy to plug in to your host computer with a USB cable, is an IC card reader/writer capable of reading contactless IC cards.

General Specification

Clock frequency(ies) in the system : 13.56MHz (CPU), 12MHz (USB Interface)

Radio Specification

Equipment Type : Transceiver
Frequency of Operation : 13.56MHz
Type of Modulation : Amplitude Modulate
Antenna Type : loop antenna
Antenna Connector Type : fixed
Power Supply (inner) : DC4.1V, DC3.5V

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SECTION 3: Test specification, procedures & results

3.1 Test Specification

Test Specification : FCC Part15 Subpart C: 2009, final revised on December 2, 2009

Title : FCC 47CFR Part15 Radio Frequency Device Subpart C Intentional Radiators
Section 15.207 : Conducted limits
Section 15.225 : Operation within the band 13.110-14.010MHz

3.2 Procedures and results

Item	Test Procedure	Specification	Worst margin	Results	Remarks
Conducted emission	ANSI C63.4:2009 7. AC powerline conducted emission measurements	Section 15.207	[QP] 16.5dB, 0.30561MHz, N (Standby mode) [AV] 7.1dB, 0.30561MHz, N (Standby mode)	Complied	-
Electric Field Strength of Fundamental Emission	ANSI C63.4:2009 13. Measurement of intentional radiators	Section 15.225(a)	50.9dB, 13.56MHz QP, 0deg. (Transmitting (Tx and Rx) Without Tag mode)	Complied	Radiated
Spectrum Mask	ANSI C63.4:2009 13. Measurement of intentional radiators	Section 15.225(b)(c)	17.0dB, 14.09010MHz QP, 0deg. (Transmitting (Tx and Rx) Without Tag mode)	Complied	Radiated
20dB Bandwidth	ANSI C63.4:2009 13. Measurement of intentional radiators	Section15.215(c)	See data	Complied	Radiated
Electric Field Strength of Spurious Emission	ANSI C63.4:2009 13. Measurement of intentional radiators	Section15.209, Section 15.225 (d)	0.8dB 528.838MHz, Horizontal, QP (Transmitting (Tx and Rx) With Tag mode)	Complied	Radiated
Frequency Tolerance	ANSI C63.4:2009 13. Measurement of intentional radiators	Section15.225(e)	See data	Complied	Radiated

Note: UL Japan, Inc.'s EMI Work Procedures No.QPM05 and QPM15

FCC 15.31 (e)

This EUT provides stable voltage (DC5.0V) constantly to RF Part regardless of input voltage. Therefore, this EUT complies with the requirement.

FCC Part 15.203 Antenna requirement

It is impossible for end users to replace the antenna, because the antenna is mounted inside of the EUT. Therefore, the equipment complies with the antenna requirement of Section 15.203.

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3.3 Addition to standard

Item	Test Procedure	Specification	Worst margin	Results	Remarks
99% Occupied Band Width	RSS-Gen 4.6.1	RSS-Gen 4.6.1	N/A	N/A	N/A

Other than above, no addition, exclusion nor deviation has been made from the standard.

3.4 Uncertainty

EMI

The following uncertainties have been calculated to provide a confidence level of 95% using a coverage factor k=2.

Test room (semi-anechoic chamber)	Conducted emission (+dB)
	150kHz-30MHz
No.1	2.6dB
No.2	2.9dB
No.3	3.3dB
No.4	2.8dB

Test room (semi-anechoic chamber)	Radiated emission (10m*)(+dB)			Radiated emission (3m*)(+dB)					
	9kHz -30MHz	30MHz -300MHz	300MHz -1GHz	(3m*)(+dB)					(1m*)(+dB)
				9kHz -30MHz	30MHz -300MHz	300MHz -1GHz	1GHz -18GHz	18GHz -26.5GHz	
No.1	2.7dB	4.8dB	5.0dB	2.9dB	4.8dB	5.0dB	3.9dB	4.5dB	4.4dB
No.2	-	-	-	3.5dB	4.8dB	5.1dB	4.0dB	4.3dB	4.2dB
No.3	-	-	-	3.8dB	4.6dB	4.7dB	4.0dB	4.5dB	4.4dB
No.4	-	-	-	3.5dB	4.4dB	4.9dB	4.0dB	4.6dB	4.5dB

*10m/3m/1m = Measurement distance

Frequency counter (±)	
Normal condition	Extreme condition
7×10^{-6}	9×10^{-6}

Conducted emission test

The data listed in this test report has enough margin, more than the site margin.

Radiated emission test (3m and 10m)

The data listed in this report meets the limits unless the uncertainty is taken into consideration.

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3.5 Test Location

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	FCC Registration Number	IC Registration Number	Width x Depth x Height (m)	Size of reference ground plane (m) / horizontal conducting plane	Other rooms
No.1 semi-anechoic chamber	313583	2973C-1	19.2 x 11.2 x 7.7m	7.0 x 6.0m	No.1 Power source room
No.2 semi-anechoic chamber	655103	2973C-2	7.5 x 5.8 x 5.2m	4.0 x 4.0m	-
No.3 semi-anechoic chamber	148738	2973C-3	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.3 Preparation room
No.3 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.4 semi-anechoic chamber	134570	2973C-4	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.4 Preparation room
No.4 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.5 semi-anechoic chamber	-	-	6.0 x 6.0 x 3.9m	6.0 x 6.0m	-
No.6 shielded room	-	-	4.0 x 4.5 x 2.7m	4.75 x 5.4 m	-
No.6 measurement room	-	-	4.75 x 5.4 x 3.0m	4.75 x 4.15 m	-
No.7 shielded room	-	-	4.7 x 7.5 x 2.7m	4.7 x 7.5m	-
No.8 measurement room	-	-	3.1 x 5.0 x 2.7m	N/A	-
No.9 measurement room	-	-	8.0 x 4.5 x 2.8m	2.0 x 2.0m	-
No.10 measurement room	-	-	2.6 x 2.8 x 2.5m	2.4 x 2.4m	-
No.11 measurement room	-	-	3.1 x 3.4 x 3.0m	2.4 x 3.4m	-

* Size of vertical conducting plane (for Conducted Emission test) : 2.0 x 2.0m for No.1, No.2, No.3, and No.4 semi-anechoic chambers and No.3 and No.4 shielded rooms.

3.6 Test set up, Data of EMI, and Test instruments

Refer to APPENDIX.

SECTION 4: Operation of E.U.T. during testing

4.1 Operating Modes

The mode is used :

Mode
(1) Transmitting (Tx and Rx) with Tag mode
(2) Transmitting (Tx and Rx) without Tag mode
(3) Transmitting (Tx and Rx) without Tag (Antenna: 50Ω terminated) mode
(4) Standby mode
(5) Continuous Transmitting mode
The EUT was operated in a manner similar to typical use during the tests. The EUT Transmits and Receives at the same time and there is no receiving mode.

Test Item	Operating mode*
Conducted emission	(1), (2), (3), (4)
Electric Field Strength of Fundamental Emission	(1), (2)
Spectrum Mask	(1), (2)
Electric Field Strength of Spurious Emission	(1), (2)
20dB Bandwidth	(1)
Frequency Tolerance	(5)

Justification: The system was configured in typical fashion (as a customer would normally use it) for testing.

Frequency Tolerance:

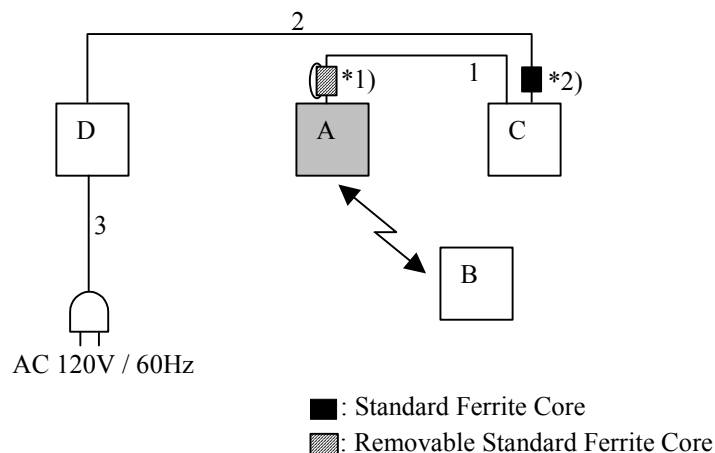
Temperature : -30deg.C to +50deg.C Step 10deg.C

Voltage : Normal Voltage DC 5.0V

Maximum Voltage DC 5.75V, Minimum Voltage DC 4.25V (DC 5.0V ±15%)

*This EUT provides stable voltage (DC5.0V) constantly to RF Part regardless of input voltage

4.2 Configuration and peripherals



*Cabling and setup were taken into consideration and test data was taken under worse case conditions.

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Description of EUT and Support equipment

No.	Item	Model number	Serial number	Manufacturer	Remark
A	Contactless IC Card Reader/Writer	PR-450UDM	4665006390811487	DENSO WAVE INCORPORATED	EUT
B	Tag	-	001	-	-
C	Personal Computer	2672-N6J	99-AYPWZ 03/10	IBM	-
D	AC Adapter	02K6810	11S02K6810Z1Z3 BJ236551	IBM	-

List of cables used

No.	Name	Length (m)	Shield		Remark
			Cable	Connector	
1	USB Cable	1.2	Shielded	Shielded	Ferrite Core: 2 turns *1)
2	DC Cable	1.8	Shielded	Shielded	Ferrite Core: 1 turns *2)
3	AC Cable	1.0	Unshielded	Unshielded	-

<Notes for Ferrite cores>

*1) 1 Ferrite Core, Model No. USB-4 (Manufacturer: KITAGAWA INDUSTRIES CO., LTD.), 5cm from Item A, 2 turns

*This is Removal Ferrite Core that is included in finished goods.

*2) Generally ferrite core is attached to the DC cable of Personal Computer. Therefore the test was performed with the core.

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SECTION 5: Conducted emission

Test Procedure and conditions

EUT was placed on a urethane platform of nominal size, 1.0m by 1.5m, raised 0.8m above the conducting ground plane. The rear of tabletop was located 40cm to the vertical conducting plane. The rear of EUT, including peripherals aligned and flushed with rear of tabletop. All other surfaces of tabletop were at least 80cm from any other grounded conducting surface. EUT was located 80cm from a Line Impedance Stabilization Network (LISN)/ Artificial mains Network (AMN) and excess AC cable was bundled in center.

For the tests on EUT with other peripherals (as a whole system)

I/O cables that were connected to the peripherals were bundled in center. They were folded back and forth forming a bundle 30cm to 40cm long and were hanged at a 40cm height to the ground plane. All unused 50ohm connectors of the LISN(AMN) were resistivity terminated in 50ohm when not connected to the measuring equipment.

The AC Mains Terminal Continuous disturbance Voltage has been measured with the EUT in a Semi Anechoic Chamber or a Measurement Room.

The EUT was connected to a LISN (AMN).

An overview sweep with peak detection has been performed.

The test results and limit are rounded off to one decimal place, so some differences might be observed.

Detector : QP and AV
Measurement range : 0.15-30MHz
Test data : APPENDIX
Test result : Pass

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SECTION 6: Radiated emission (Fundamental , Spurious Emission and Spectrum Mask)

Test Procedure

EUT was placed on a urethane platform of nominal size, 0.5m by 1.0m, raised 0.8m above the conducting ground plane. The Radiated Electric Field Strength has been measured in a Semi Anechoic Chamber with a ground plane. The height of the measuring antenna varied between 1 and 4m and EUT was rotated a full revolution in order to obtain the maximum value of the electric field strength. The measurements were performed for both vertical (angle of loop antenna: 0deg., 45deg., 90deg., and 135 deg.) and horizontal antenna polarization with the Test Receiver, or the Spectrum Analyzer. The measurements were made with the following detector function of the test receiver and the Spectrum analyzer (in linear mode). The test was made with the detector (RBW/VBW) in the following table. When using Spectrum analyzer, the test was made with adjusting span to zero by using peak hold.

Test Antennas are used as below;

Frequency	Below 30MHz	30MHz to 300MHz	300MHz to 1GHz
Antenna Type	Loop	Biconical	Logperiodic

Frequency	From 9kHz to 90kHz and From 110kHz to 150kHz	From 90kHz to 110kHz	From 150kHz to 490kHz	From 490kHz to 30MHz	From 30MHz to 1GHz
Instrument used	Test Receiver				
Detector	PK/AV	QP	PK/AV	QP	QP
IF Bandwidth	200Hz	200Hz	9kHz	9kHz	120kHz

- The carrier level and noise levels were confirmed at each position of X, Y and Z axes of EUT to see the position of maximum noise, and the test was made at the position that has the maximum noise.

* FCC Part 15 Section 15.31 (f)(2) / IC RSS-Gen 4.11 (9kHz-30MHz)

$$9\text{kHz} - 490\text{kHz} [\text{Limit at } 3\text{m}] = [\text{Limit at } 300\text{m}] - 40 \log\left(\frac{3}{300}\right)$$

$$490\text{kHz} - 30\text{MHz} [\text{Limit at } 3\text{m}] = [\text{Limit at } 30\text{m}] - 40 \log\left(\frac{3}{30}\right)$$

Measurement range : 0.09M-1GHz
Test data : APPENDIX
Test result : Pass

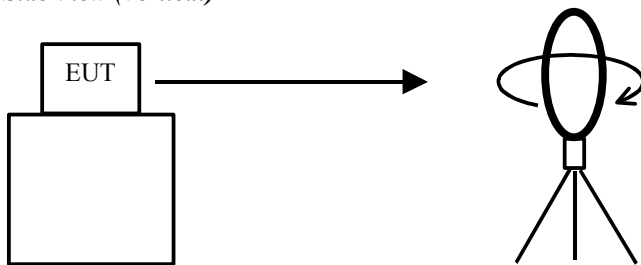
SECTION 7: Other test

Test	Span	RBW	VBW	Sweep time	Detector	Trace	Instrument used
20dB Bandwidth	100kHz	1kHz	3kHz	Auto	Peak	Max Hold	Spectrum Analyzer
99% Occupied Bandwidth	Enough width to display 20dB Bandwidth	1 to 3% of Span	Three times of RBW	Auto	Peak	Max Hold	Spectrum Analyzer
Frequency Tolerance	-	-	-	-	-	-	Frequency counter

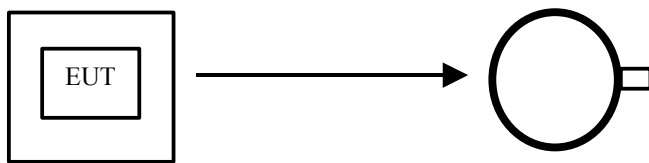
Test data : APPENDIX
Test result : Pass

Figure 1: Direction of the Loop Antenna

Side View (Vertical)

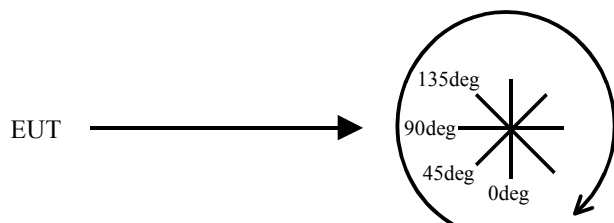


Top View (Horizontal)



Antenna was not rotated.

Top View (Vertical)



Front side: 0 deg.
Forward direction: clockwise